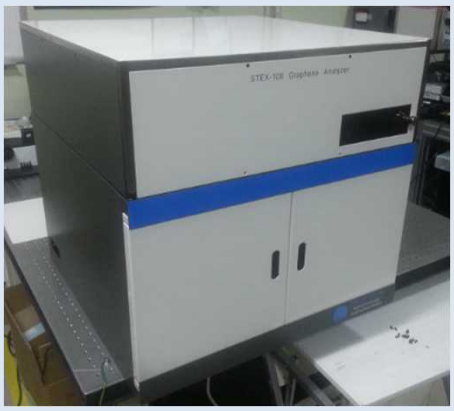
DONG WOO OPTRON Co., Ltd.

STEX-100. Compact confocal micro Raman Mapping System

KEY FEATURES

- All in on case : built in laser & spectrometer
- Robust design : stable and easy alignment
- Detachable optical system : save the time consuming of returning, inspection
- Affordable price for your application



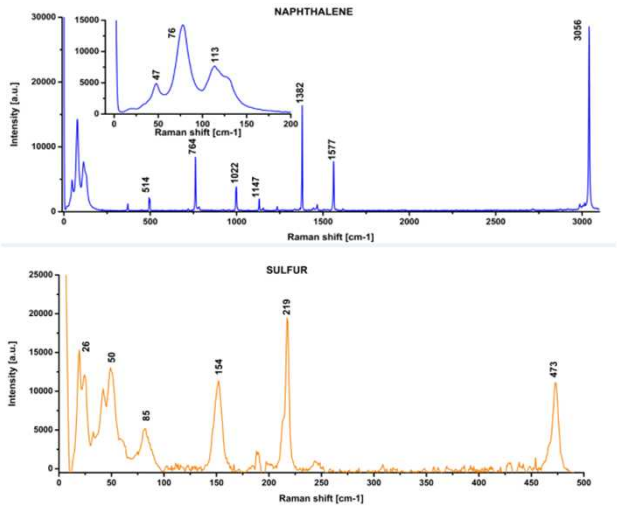
APPLICATION

- Carbon material(CNT, Graphene) Surface and subsurface analyze
- 2D semiconductor(MoS2, MoSe2,WS2)

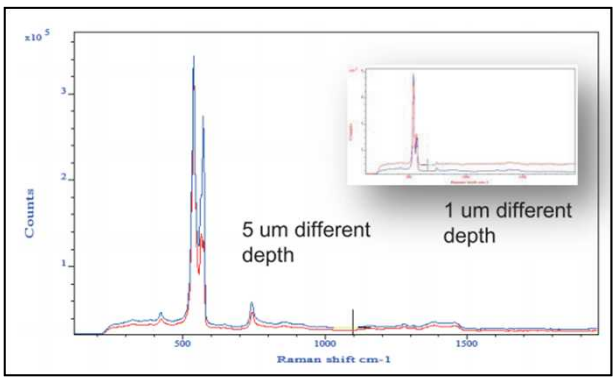
SPECIFICATION

Detecting Range	50 ~ 3500 cm-1 (or 4200 cm-1 selectable) < 25 cm-1 available @532 nm
System resolution	0.2 nm/pixel of CCD (built in)
Spatial resolution	XY - 0.05 um(Min.) 0.1 um(typical) /Z – 1um(high resolution available on request)
Spectrograph	Aberration corrected high throughput
Detector	TE cooled high performance CCD
Laser power control	0.1% ~ 100 % (up to 6 different power level and other level available on request)
Laser excitation	Up to two internal lasers(320, 532, 632.8 and 785 nm) fiber optic external laser available
Dimension	610(W)X600(D)X600(H) mm
Optional	Low temp & Mapping image

PERFORMANCE



◆ Raman spectrums of calibration standards measured b y STEX-100: lattice naphthalene (upper) and solid sul fur (lower)



◆ Confocality
Sensitivity about structure of GaN by depth